Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/274,157	MCVEIGH ET AL.	
Examiner	Art Unit	
Richard Lee	2621	

SEARCHED			
Class	Subclass	Date	Examiner
Updated	Search	2/7/2007	RL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR